#### DESCRIPTION

The SPN7002L is the N-Channel enhancement mode field effect transistors are produced using high cell density DMOS technology. These products have been designed to minimize on-state resistance while provide rugged, reliable, and fast switching performance. They can be used in most applications requiring up to 300mA DC and can deliver pulsed currents up to 0.8A. These products are particularly suited for low voltage, low current applications such as small servo motor control, power MOSFET gate drivers, and other switching applications.

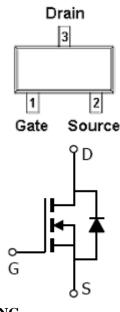
#### APPLICATIONS

- Drivers: Relays, Solenoids, Lamps, Hammers, Display, Memories, Transistors, etc.
- High saturation current capability. Direct Logic-Level Interface: TTL/CMOS
- Battery Operated Systems
- Solid-State Relays

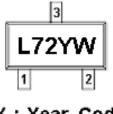
#### FEATURES

- 50V/0.30A, RDS(ON)=  $3.5\Omega@VGS=10V$
- 50V/0.25A, RDS(ON)=  $5.5\Omega@VGS=4.5V$
- 50V/0.05A, RDS(ON)=  $7.5\Omega@VGS=2.5V$
- Super high density cell design for extremely low RDS (ON)
- Exceptional on-resistance and maximum DC current capability
- SOT-23 package design

#### PIN CONFIGURATION(SOT-23)



## PART MARKING



Y : Year Code W : Week Code



### PIN DESCRIPTION

Pin	Symbol	Description
1	G	Gate
2	S	Source
3	D	Drain

#### **ORDERING INFORMATION**

Part Number	Package	Part Marking
SPN7002LS23RGB	SOT-23	L72YW

**Week Code** :  $A \sim Z(1 \sim 26)$ ;  $a \sim z(27 \sim 52)$ 

X SPN7002LS23RGB : Tape Reel ; Pb – Free; Halogen – Free

#### ABSOULTE MAXIMUM RATINGS (TA=25°C Unless otherwise noted)

Parameter		Symbol	Typical	Unit	
Drain-Source Voltage		VDSS	50	V	
Gate –Source Voltage - Continuous		VGSS	±20	V	
Gate –Source Voltage - Non Repetitive ( $t_p < 50 \mu s$ )		VGSS	±40	V	
Continuous Drain Current(TJ=150°C)	Ta=25°C	ID	0.3	А	
Pulsed Drain Current (*)		Idм	0.8	А	
Power Dissipation	TA=25°C	PD	0.35	W	
Operating Junction Temperature		τJ	-55 ~ 150	°C	
Storage Temperature Range		Tstg	-55 ~ 150	°C	
Thermal Resistance-Junction to Ambient		Roja	375	°C/W	

(\*) Pulse width limited by safe operating area

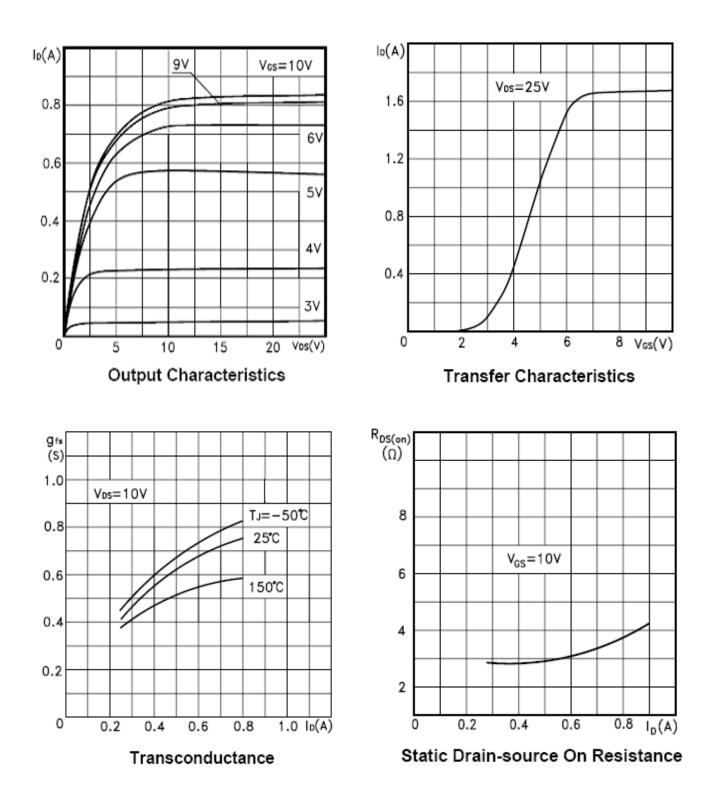
## **ELECTRICAL CHARACTERISTICS** (TA=25°C Unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Тур	Max.	Unit
Static						4
Drain-Source Breakdown Voltage	V(BR)DSS	VGs=0V,ID=250uA	50			V
Gate Threshold Voltage	VGS(th)	/GS(th) VDS=VGS,ID=250uA 0.8		1.25	1.5	V
Gate Leakage Current	Igss	VDS=0V,VGS=±20V			±100	nA
Zero Gate Voltage Drain Current		Vds=45V,Vgs=0V			1	uA
	IDSS	Vds=45V,Vgs=0V Tj=125°C			10	
		Vgs=10V,Id=0.30A		2.5	3.5	Ω
Drain-Source On-Resistance	RDS(on)	VGS= 4.5V,ID=0.25A		3.3	5.5	
		VGS= 2.5V,ID=0.05A		5.0	7.5	
Source-drain Current	ISD				0.35	A
Source-drain Current (pulsed) Forward Transconductance	ISDM (2) Gfs(1)	$V_{DS} = 10 V, I_{D} = 0.5 A$		0.6	1.4	A S
Diode Forward Voltage	VsD(1)	$V_{GS} = 0 V, I_S = 0.12A$		0.85	1.5	V
Dynamic						
Total Gate Charge	Qg			1.4	2.0	nC
Gate-Source Charge	Qgs	$V_{DD} = 30 V, I_D = 1 A, V_{GS} = 5 V$		0.8		
Gate-Drain Charge	Qgd	V G S = J V		0.5		
Input Capacitance	Ciss			43		pF
Output Capacitance	Coss	$V_{DS} = 25 V, f = 1 MHz,$ $V_{GS} = 0$		20		
Reverse Transfer Capacitance	Crss	105 - 0		6		
Turn-On Time	td(on)			5		- ns
	tr	$V_{DD} = 30 V, I_D = 0.5 A$		15		
Turn Off Time	td(off)	$R_G = 4.7\Omega V_{GS} = 4.5 V$		7		
Turn-Off Time	tf			8		

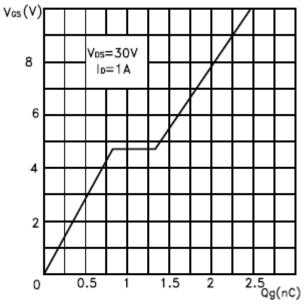
(1) Pulsed: Pulse duration =  $300 \ \mu s$ , duty cycle 1.5 %.

(2) Pulse width limited by safe operating area.

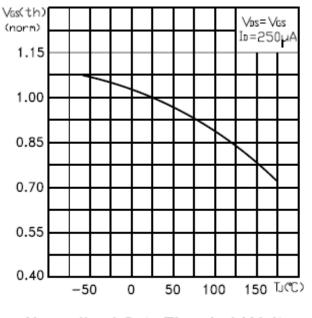
## TYPICAL CHARACTERISTICS



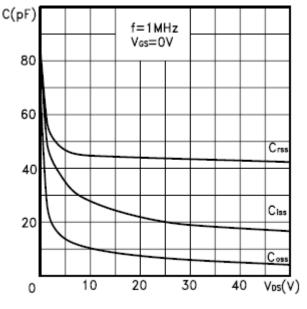
## TYPICAL CHARACTERISTICS



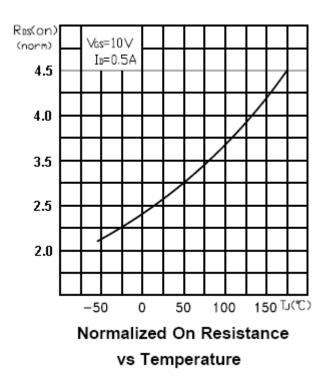
Gate Charge vs Gate-source Voltage



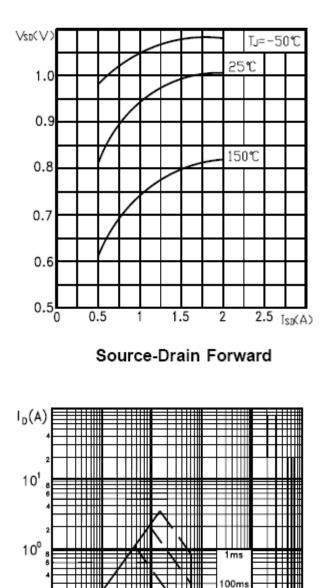
Normalized Gate Threshold Voltage vs Temperature



Capacitance Variations



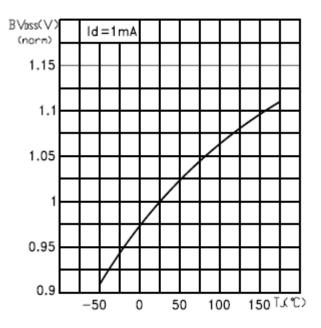
## TYPICAL CHARACTERISTICS



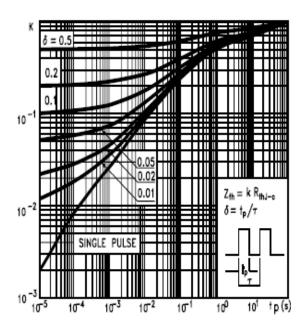
10ms

Tj=150°C Tc=25°C Single pulse

V<sub>DS</sub> (V)



Normalized BVDSS vs Temperature



Thermal Impedance

10°

4

آ 10 <sup>1</sup>

Safe Operating Area

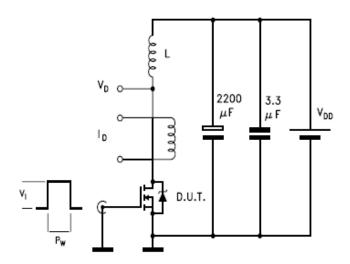
<sup>68</sup>10<sup>2</sup>

 $10^{-1}$ 

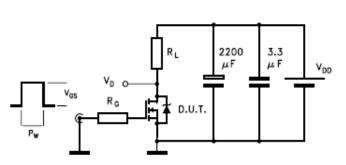
 $10^{-2}$ 

10-1

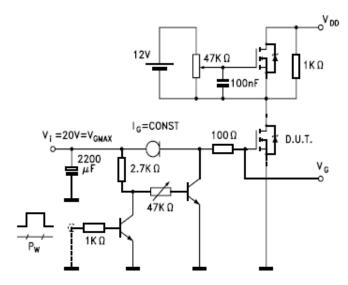
TYPICAL TESTING CIRCUIT



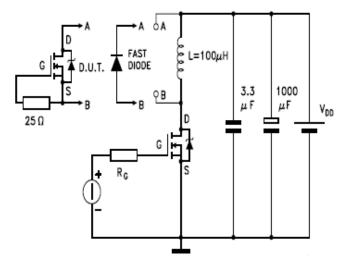
**Unclamped Inductive Load Test** 



Switching Times Test Circuit

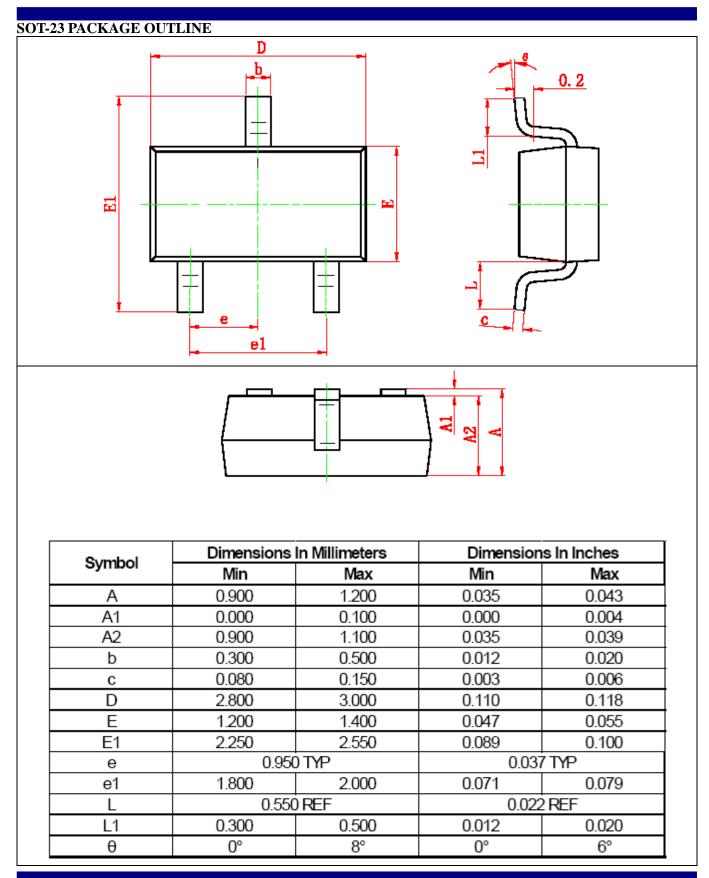


Gate Charge Test Circuit



Test Circuit For Inductive Load Switching and Diode Recovery Times







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